

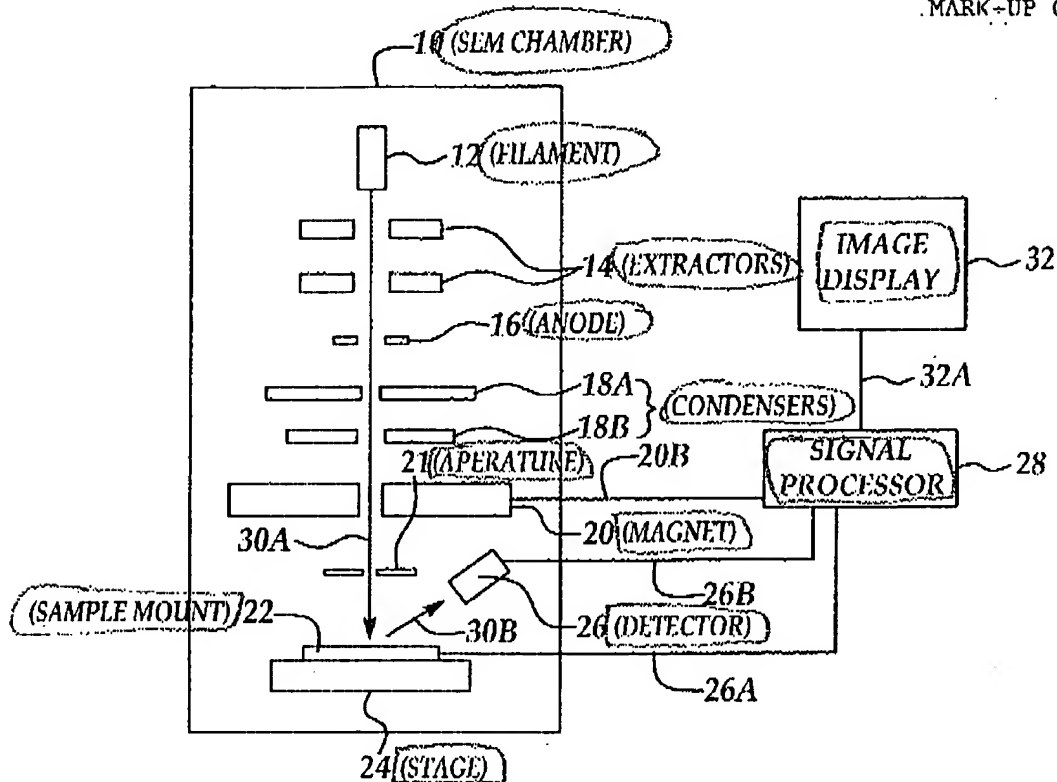
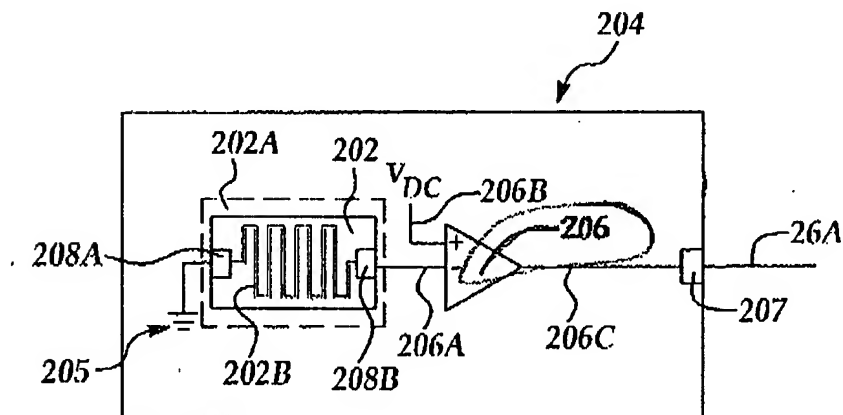
Inventor: Hui-Chuan Hung

Serial No.: 10/656,754 Filed: 09/06/2003

For: In-Situ Electron Beam Induced Current Detection

Attorney Doc. No.: 67,200-1152

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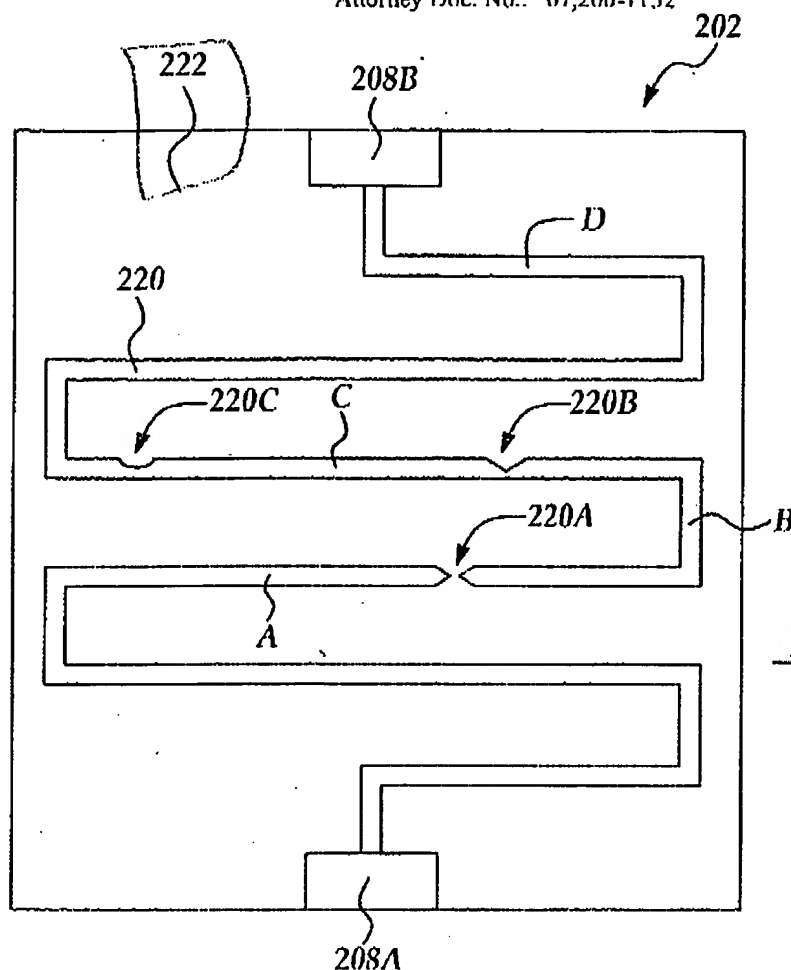
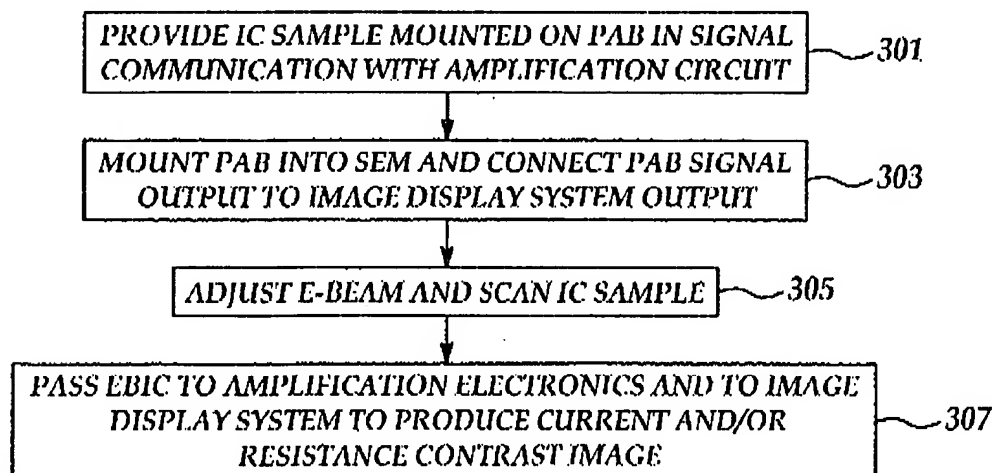
Figure 1Figure 2A

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Figure 2BFigure 3

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REPLACEMENT SHEET

10 (SEM CHAMBER)

12 (FILAMENT)

14 (EXTRACTORS)

16 (ANODE)

18A } (CONDENSERS)

18B }

21 (APERTURE)

20 (MAGNET)

20B

22 (SAMPLE MOUNT)

24 (STAGE)

26 (DETECTOR)

26A

26B

28 (SIGNAL PROCESSOR)

30A

30B

32 (IMAGE DISPLAY)

32A

THEY CAN'T, BUT WE CAN

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